



THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Application of :  
Masatoshi YASUTAKE et al. :  
Serial No. 10/775,724 : Group Art Unit - 2823  
Filed: February 10, 2004 : Examiner: Quovaunda Jefferson  
For: PREPARATION OF SAMPLE CHIP, :  
METHOD OF OBSERVING WALL :  
SURFACE THEREOF AND SYSTEM :  
THEREFOR : Docket No. S004-5210

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MS FEE AMENDMENT  
COMMISSIONER FOR PATENTS  
P.O. BOX 1450  
ALEXANDRIA, VA 22313-1450

RESPONSE

S I R:

In response to the Office Action dated August  
30, 2005, applicants amend their application as follows:

ELECTION OF INVENTION:

Applicants provisionally elect, with traverse,  
the invention characterized by the Examiner as Invention I  
drawn to a method of preparing a sample chip and observing  
its wall surface, and submit that claims 1-16 are readable  
on the elected invention.